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Sheet 1 of 1

ATTORNEY DOCKET NO.

SERIAL NO.

9319S-000262

09/943,748

APPLICANT

Hiroki Nakahara

FILING DATE

GROUP

August 30, 2001

2871

**U.S. PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	gm	2000-2144474	8/4/2000	Japan		X	
2.		07-333626	12/22/1995	Japan		X	
3.		11-190854	3/13/1999	Japan		X	
4.		04-163426	6/9/1992	Japan		X	
5.		06-160791	6/7/1994	Japan		X	
6.		11-125827	5/11/1999	Japan		X	
7.		11-109389	4/23/1999	Japan		X	
8.		10-104642	4/24/1998	Japan		X	
9.		07-084230	3/31/1995	Japan		X	
10.	gm	05-072542	3/26/1993	Japan		X	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.	gm	Search Report from corresponding Japanese Patent Application No. 2001-236576

Examiner:

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**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes No	
1.	SN	10-161139	19.06.1998	Japan		XXXX	
2.	SN	10-062792	06.03.1998	Japan		XXXX	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.	SN	Korean Office Action 2003/2/27 No English translation

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